74FST3126

4-Bit Bus Switch

The ON Semiconductor 74FST3126 is a quad, high performance switch. The device is CMOS TTL compatible when operating between 4 and 5.5 Volts. The device exhibits extremely low R_{ON} and adds nearly zero propagation delay. The device adds no noise or ground bounce to the system.

The device consists of four independent 1–bit switches with separate Output/Enable (OE) pins. Port A is connected to Port B when OE is high. If OE is low, the switch is high Z.

- R_{ON} < 4 Ω Typical
- Less Than 0.25 ns–Max Delay Through Switch
- Nearly Zero Standby Current
- No Circuit Bounce
- Control Inputs are TTL/CMOS Compatible
- Pin–For–Pin Compatible With QS3126, FST3126, CBT3126
- All Popular Packages: QSOP–16, TSSOP–14, SOIC–14

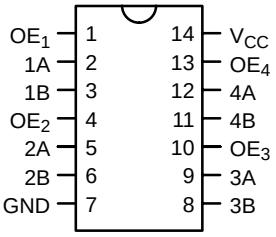


Figure 1. Pin Assignment for SOIC and TSSOP

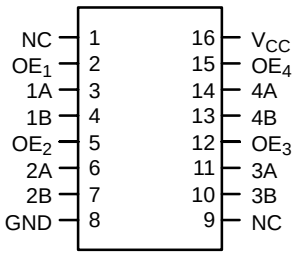


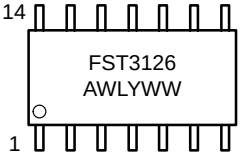
Figure 2. Pin Assignment for QSOP

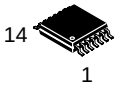
ON Semiconductor™

http://onsemi.com

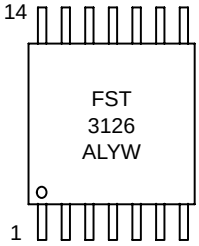
MARKING DIAGRAMS

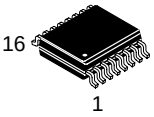
SO–14
D SUFFIX
CASE 751A



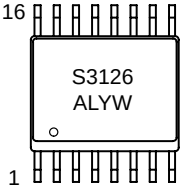


TSSOP–14
DT SUFFIX
CASE 948G





QSOP–16
QS SUFFIX
CASE 492



A = Assembly Location
L, WL = Wafer Lot
Y = Year
W, WW = Work Week

PIN NAMES

Pin	Description
OE_1, OE_2, OE_3, OE_4	Bus Switch Enables
1A, 2A, 3A, 4A	Bus A
1B, 2B, 3B, 4B	Bus B
NC	Not Connected

ORDERING INFORMATION

Device	Package	Shipping
74FST3126D	SO–14	55 Units/Rail
74FST3126DR2	SO–14	2500 Units/Reel
74FST3126DT	TSSOP–14	96 Units/Rail
74FST3126DTR2	TSSOP–14	2500 Units/Reel
74FST3126QS	QSOP–16	98 Units/Rail
74FST3126QSR	QSOP–16	2500 Units/Reel

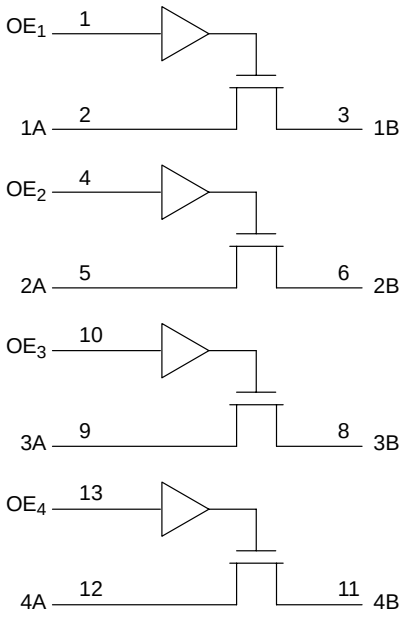


Figure 3. Logic Diagram

TRUTH TABLE

Inputs	Outputs
OE	A, B
L	Z
H	A = B

MAXIMUM RATINGS

Symbol	Parameter		Value	Unit
V_{CC}	DC Supply Voltage		−0.5 to +7.0	V
V_I	DC Input Voltage		−0.5 to +7.0	V
V_O	DC Output Voltage		−0.5 to +7.0	V
I_{IK}	DC Input Diode Current	V_I < GND	−50	mA
I_{OK}	DC Output Diode Current	V_O < GND	−50	mA
I_O	DC Output Sink Current		128	mA
I_{CC}	DC Supply Current per Supply Pin		±100	mA
I_{GND}	DC Ground Current per Ground Pin		±100	mA
T_{STG}	Storage Temperature Range		−65 to +150	°C
T_L	Lead Temperature, 1 mm from Case for 10 Seconds		260	°C
T_J	Junction Temperature Under Bias		+150	°C
θ_{JA}	Thermal Resistance (Note 1)	SOIC TSSOP QSOP	125 170 200	°C/W
MSL	Moisture Sensitivity		Level 1	
F_R	Flammability Rating	Oxygen Index: 28 to 34	UL 94 V–0 @ 0.125 in	
V_{ESD}	ESD Withstand Voltage	Human Body Model (Note 2) Machine Model (Note 3)	>2000 >200	V
$I_{LATCH–UP}$	Latch–Up Performance	Above V_{CC} and Below GND at 85°C (Note 4)	±500	mA

Maximum Ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute maximum–rated conditions is not implied. Functional operation should be restricted to the Recommended Operating Conditions.

1. Measured with minimum pad spacing on an FR4 board, using 10 mm–by–1 inch, 2–ounce copper trace with no air flow.
2. Tested to EIA/JESD22–A114–A.
3. Tested to EIA/JESD22–A115–A.
4. Tested to EIA/JESD78.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Min	Max	Unit
V_{CC}	Supply Voltage	Operating, Data Retention Only	4.0	5.5	V
V_I	Input Voltage	(Note 5)	0	5.5	V
V_O	Output Voltage	(HIGH or LOW State)	0	V_{CC}	V
T_A	Operating Free–Air Temperature		−40	+85	°C
$\Delta t/\Delta V$	Input Transition Rise or Fall Rate	Switch Control Input Switch I/O	0 0	5 DC	ns/V

5. Unused control inputs may not be left open. All control inputs must be tied to a high or low logic input voltage level.

DC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Conditions	V_{CC} (V)	$T_A = -40°C$ to $+85°C$			Unit
				Min	Typ*	Max	
V_{IK}	Clamp Diode Resistance	$I_{IN} = -18mA$	4.5			−1.2	V
V_{IH}	High–Level Input Voltage		4.0 to 5.5	2.0			V
V_{IL}	Low–Level Input Voltage		4.0 to 5.5			0.8	V
I_I	Input Leakage Current	$0 \le V_{IN} \le 5.5$ V	5.5			±1.0	μA
I_{OZ}	OFF–STATE Leakage Current	$0 \le A, B \le V_{CC}$	5.5			±1.0	μA
R_{ON}	Switch On Resistance (Note 6)	$V_{IN} = 0$ V, $I_{IN} = 64$ mA	4.5		4	7	Ω
		$V_{IN} = 0$ V, $I_{IN} = 30$ mA	4.5		4	7	
		$V_{IN} = 2.4$ V, $I_{IN} = 15$ mA	4.5		8	15	
		$V_{IN} = 2.4$ V, $I_{IN} = 15$ mA	4.0		11	20	
I_{CC}	Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND, $I_{OUT} = 0$	5.5			3	μA
ΔI_{CC}	Increase In I_{CC} per Input	One input at 3.4 V, Other inputs at V_{CC} or GND	5.5			2.5	mA

*Typical values are at $V_{CC} = 5.0$ V and $T_A = 25°C$.
6. Measured by the voltage drop between A and B pins at the indicated current through the switch.

AC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Conditions	Figures	Limits				Unit
				$T_A = -40°C$ to $+85°C$				
				$V_{CC} = 4.5$ to 5.5 V		$V_{CC} = 4.0$ V		
				Min	Max	Min	Max	
t_{PHL}, t_{PLH}	Prop Delay Bus to Bus (Note 7)	V_I = OPEN	4 and 5		0.25		0.25	ns
t_{PZH}, t_{PZL}	Output Enable Time	$V_I = 7$ V for t_{PZL} V_I = OPEN for t_{PZH}	4 and 5	1.0	4.5		5.0	ns
t_{PHZ}, t_{PLZ}	Output Disable Time	$V_I = 7$ V for t_{PLZ} V_I = OPEN for t_{PHZ}	4 and 5	1.5	5.7		6.2	ns

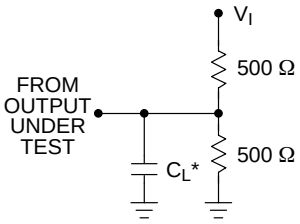
7. This parameter is guaranteed by design but is not tested. The bus switch contributes no propagation delay other than the RC delay of the typical On resistance of the switch and the 50 pF load capacitance, when driven by an ideal voltage source (zero output impedance).

CAPACITANCE (Note 8)

Symbol	Parameter	Conditions	Typ	Max	Unit
C_{IN}	Control Pin Input Capacitance	$V_{CC} = 5.0$ V	3		pF
$C_{I/O}$	Input/Output Capacitance	$V_{CC} = 5.0$ V, OE = 0 V	5		pF

8. $T_A = +25°C$, f = 1 MHz, Capacitance is characterized but not tested.

AC Loading and Waveforms



NOTES:
1. Input driven by 50 Ω source terminated in 50 Ω.
2. CL includes load and stray capacitance.
*C_L = 50 pF

Figure 4. AC Test Circuit

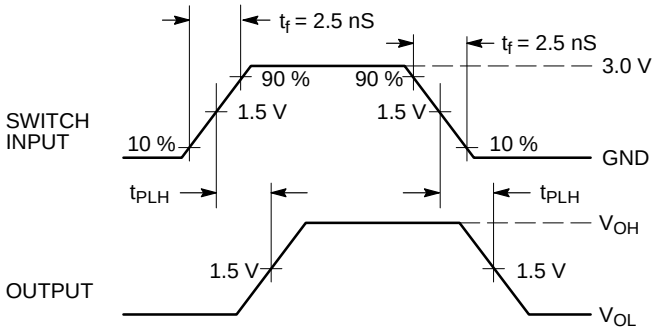


Figure 5. Propagation Delays

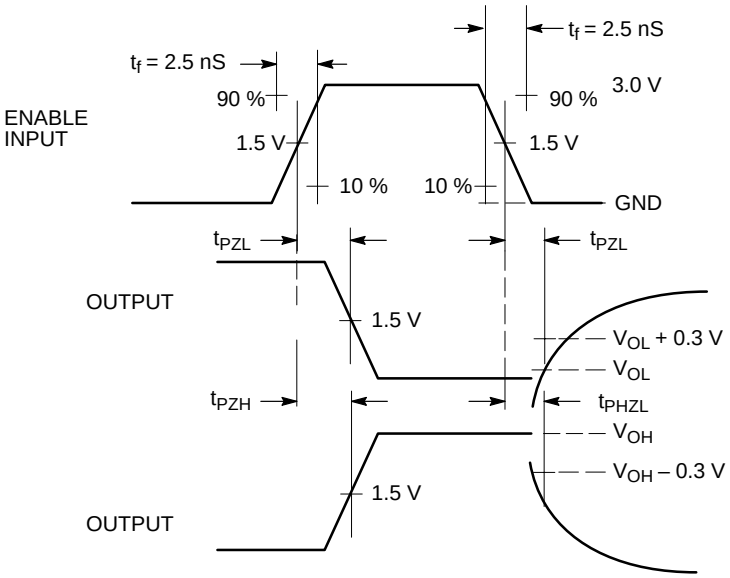
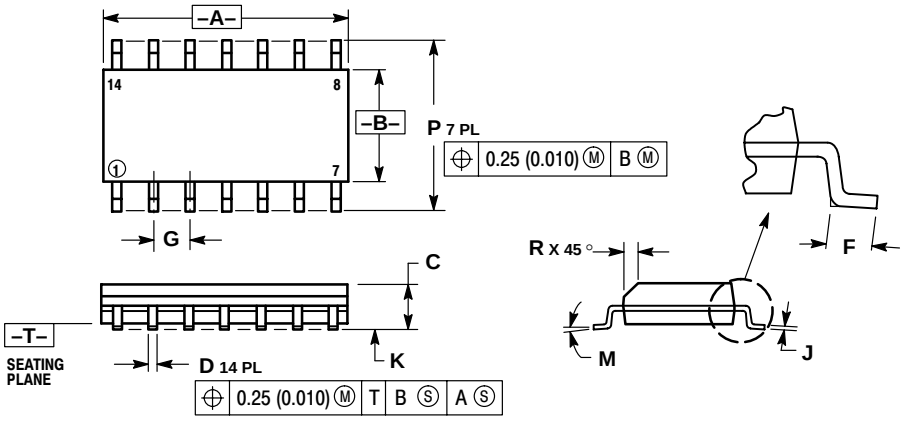


Figure 6. Enable/Disable Delays

PACKAGE DIMENSIONS

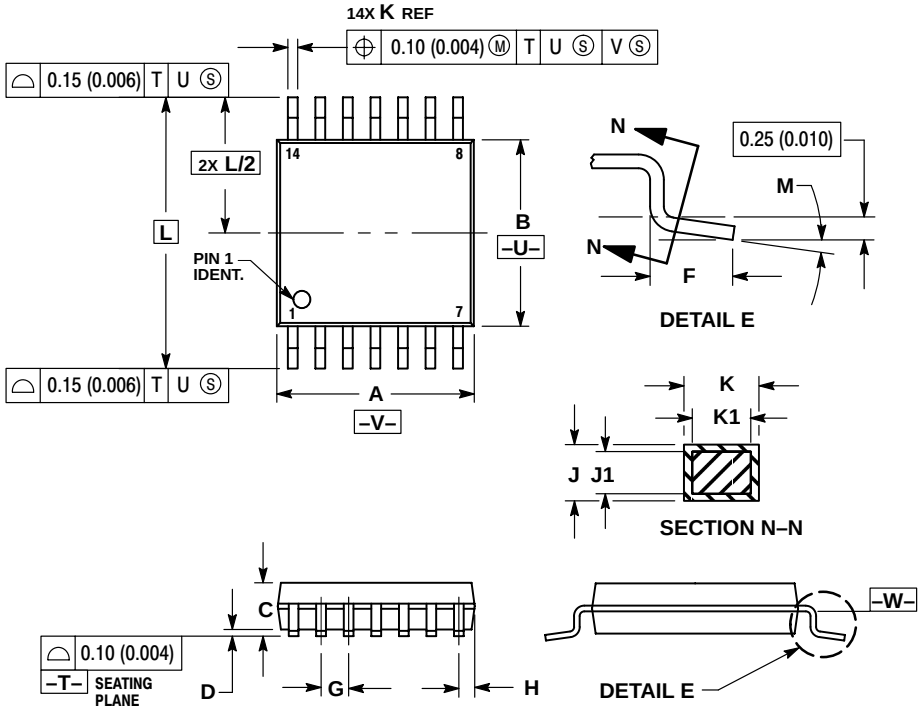
SO–14
D SUFFIX
CASE 751A–03
ISSUE F



NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	8.55	8.75	0.337	0.344
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27 BSC		0.050 BSC	
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0 °	7 °	0 °	7 °
P	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

TSSOP–14
DT SUFFIX
CASE 948G–01
ISSUE O

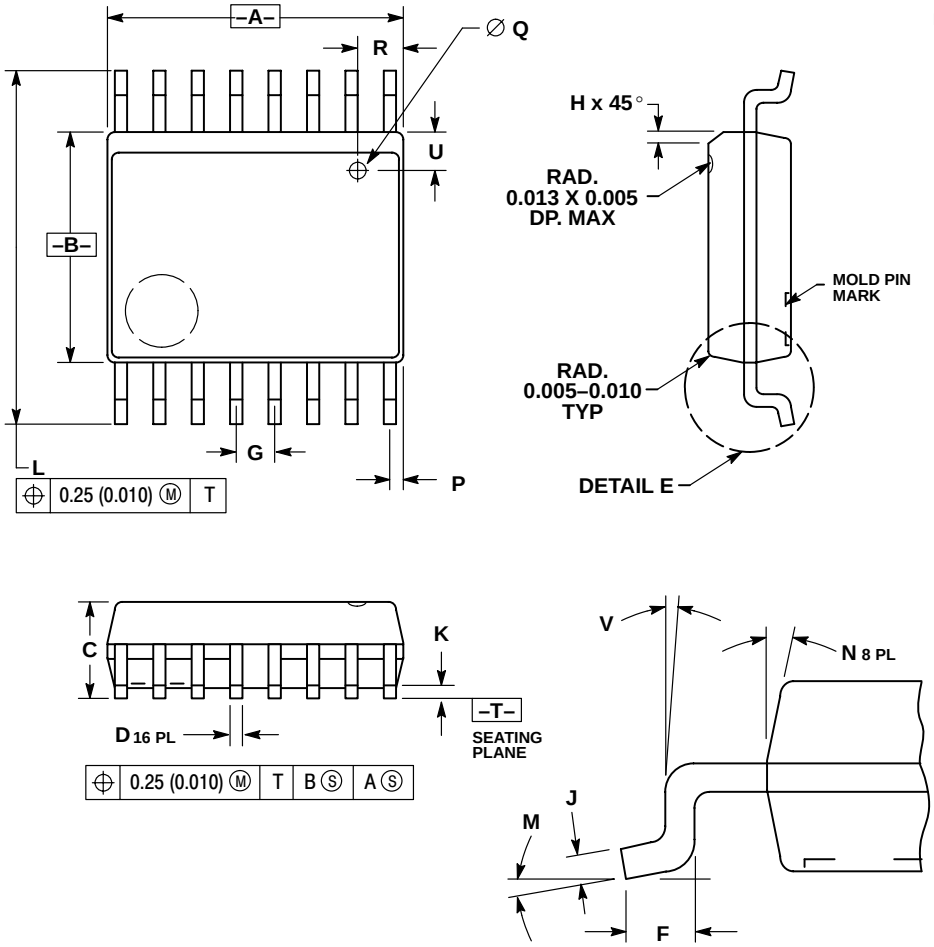


NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
7. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE –W–.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
A	4.90	5.10	0.193	0.200
B	4.30	4.50	0.169	0.177
C	---	1.20	---	0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65 BSC		0.026 BSC	
H	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
M	0 °	8 °	0 °	8 °

PACKAGE DIMENSIONS

QSOP–16
QS SUFFIX
CASE 492–01
ISSUE O



DETAIL E

NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. THE BOTTOM PACKAGE SHALL BE BIGGER THAN THE TOP PACKAGE BY 4 MILS (NOTE: LEAD SIDE ONLY). BOTTOM PACKAGE DIMENSION SHALL FOLLOW THE DIMENSION STATED IN THIS DRAWING.
4. PLASTIC DIMENSIONS DOES NOT INCLUDE MOLD FLASH OR PROTRUSIONS. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 6 MILS PER SIDE.
5. BOTTOM EJECTOR PIN WILL INCLUDE THE COUNTRY OF ORIGIN (COO) AND MOLD CAVITY I.D.

	INCHES		MILLIMETERS	
DIM	MAX	MIN	MAX	MIN
A	0.189	0.196	4.80	4.98
B	0.150	0.157	3.81	3.99
C	0.061	0.068	1.55	1.73
D	0.008	0.012	0.20	0.31
F	0.016	0.035	0.41	0.89
G	0.025 BSC		0.64 BSC	
H	0.008	0.018	0.20	0.46
J	0.0098	0.0075	0.249	0.191
K	0.004	0.010	0.10	0.25
L	0.230	0.244	5.84	6.20
M	0°	8°	0°	8°
N	0°	7°	0°	7°
P	0.007	0.011	0.18	0.28
Q	0.020 DIA		0.51 DIA	
R	0.025	0.035	0.64	0.89
U	0.025	0.035	0.64	0.89
V	0°	8°	0°	8°

PUBLICATION ORDERING INFORMATION

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